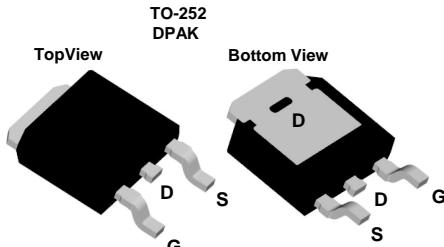
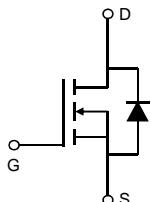


TMD70N03 N-CHANNEL POWER MOSFET

<p>General Description</p> <ul style="list-style-type: none"> Latest Trench Power MOSFET technology Very Low RDS(on) at 10VGS Low Gate Charge High Current Capability <p>Application</p> <ul style="list-style-type: none"> DC/DC Converters in Computing Isolated DC/DC Converters in Telecom and Industrial 	<p>Product Summary</p> <table style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 30%;">V_{DS}</td><td style="width: 30%;">30V</td></tr> <tr> <td>I_D (at V_{GS}=10V)</td><td>68A</td></tr> <tr> <td>R_{DS(ON)} (at V_{GS}=10V)</td><td>< 8.5mΩ</td></tr> <tr> <td>R_{DS(ON)} (at V_{GS} = 4.5V)</td><td>< 13.0mΩ</td></tr> </table> <p>100% UIS Tested 100% R_g Tested</p>	V _{DS}	30V	I _D (at V _{GS} =10V)	68A	R _{DS(ON)} (at V _{GS} =10V)	< 8.5mΩ	R _{DS(ON)} (at V _{GS} = 4.5V)	< 13.0mΩ
V _{DS}	30V								
I _D (at V _{GS} =10V)	68A								
R _{DS(ON)} (at V _{GS} =10V)	< 8.5mΩ								
R _{DS(ON)} (at V _{GS} = 4.5V)	< 13.0mΩ								

	
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Absolute Maximum Ratings T _A =25°C unless otherwise noted			
Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current ^G	I _{DS}	68	A
T _C =100°C		44.5	
Pulsed Drain Current ^C	I _{DM}	272	
Continuous Drain Current	I _{DSM}	22	A
T _A =70°C		18	
Avalanche Current ^C	I _{AS}	37	A
Avalanche energy L=0.1mH ^C	E _{AS}	68	mJ
V _{DS} Spike	V _{SPIKE}	36	V
Power Dissipation ^B	P _D	50	W
T _C =100°C		25	
Power Dissipation ^A	P _{DSM}	2.5	W
T _A =70°C		1.6	
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to 175	°C

Thermal Characteristics					
Parameter	Symbol	Typ	Max	Units	
Maximum Junction-to-Ambient ^A	t ≤ 10s	16	20	°C/W	
Maximum Junction-to-Ambient ^{A,D}		41	50	°C/W	
Maximum Junction-to-Case	R _{θJC}	2.1	3	°C/W	

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2	1.8	2.2	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$		7.4	8.5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		10.8	13.0	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		105		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current ^G				58	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		2010		pF
C_{oss}	Output Capacitance			898		pF
C_{rss}	Reverse Transfer Capacitance			124		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	0.9	1.8	2.7	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		36	49	nC
$Q_g(4.5\text{V})$	Total Gate Charge			17	23	nC
Q_{gs}	Gate Source Charge			6		nC
Q_{gd}	Gate Drain Charge			8		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		7.5		ns
t_r	Turn-On Rise Time			4.0		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			37.0		ns
t_f	Turn-Off Fall Time			7.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		14		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		20.3		nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on R_{JJA} and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.

D. The R_{JJA} is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

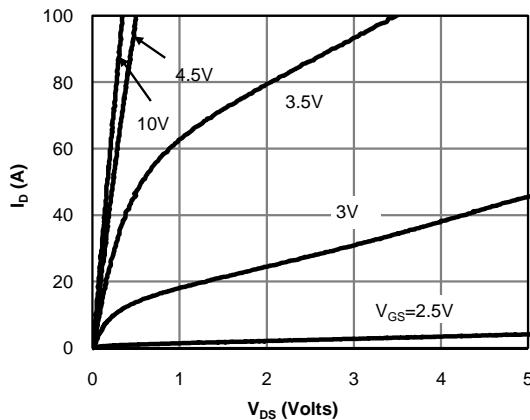


Fig 1: On-Region Characteristics (Note E)

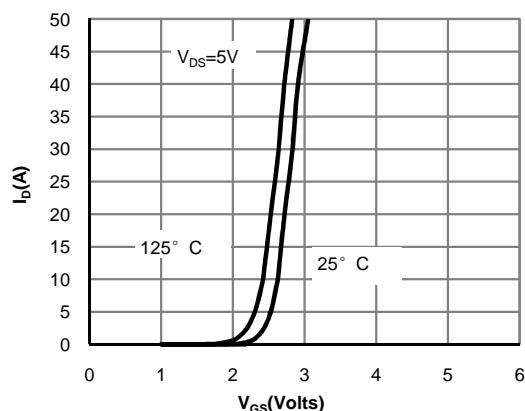


Figure 2: Transfer Characteristics (Note E)

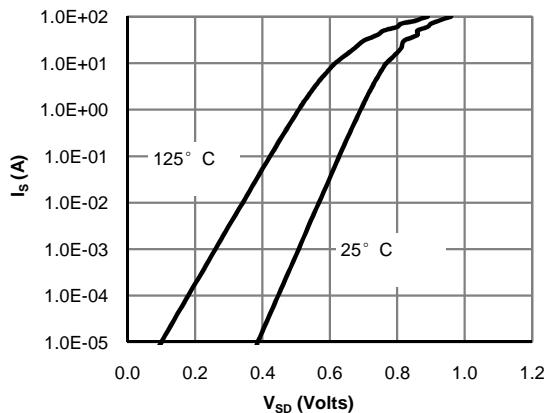


Figure 6: Body-Diode Characteristics (Note E)

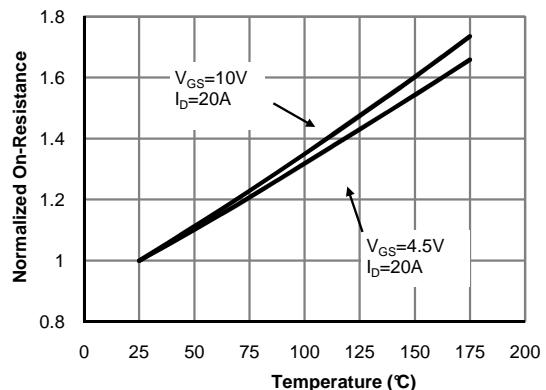


Figure 4: On-Resistance vs. Junction Temperature (Note E)

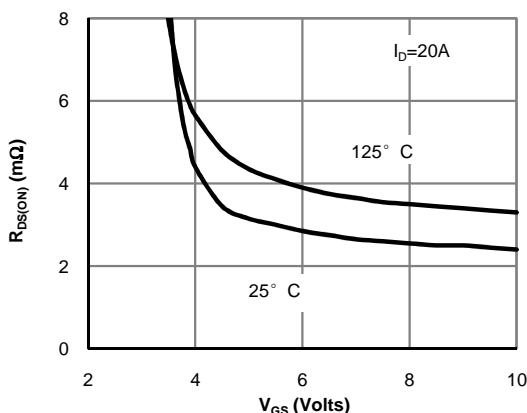


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

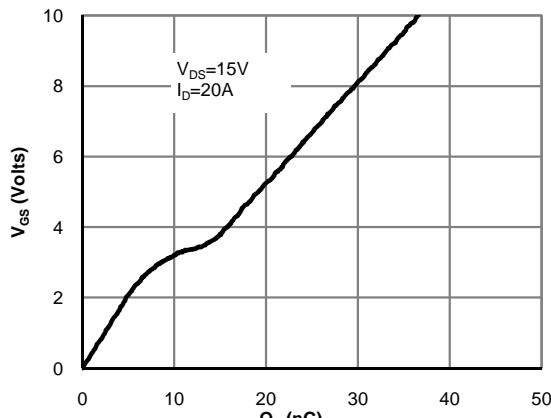


Figure 7: Gate-Charge Characteristics

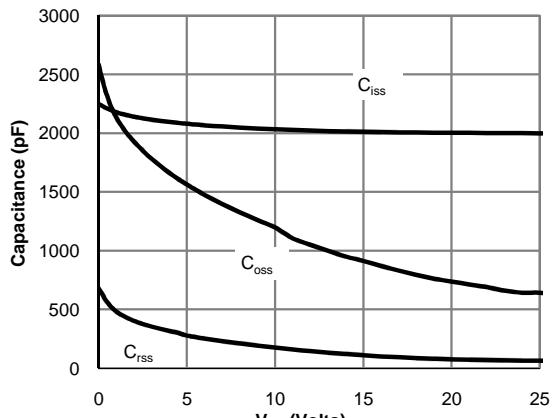


Figure 8: Capacitance Characteristics

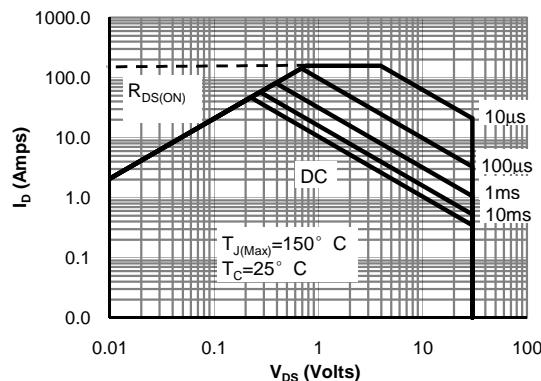


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

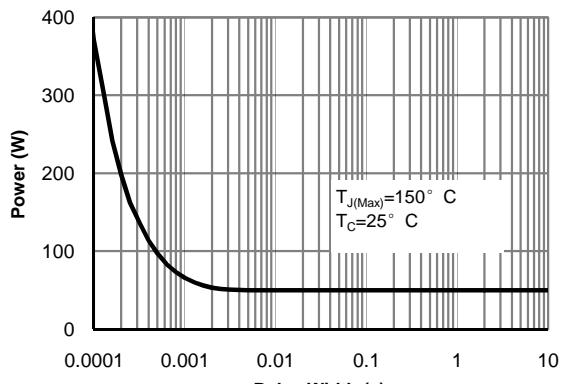


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

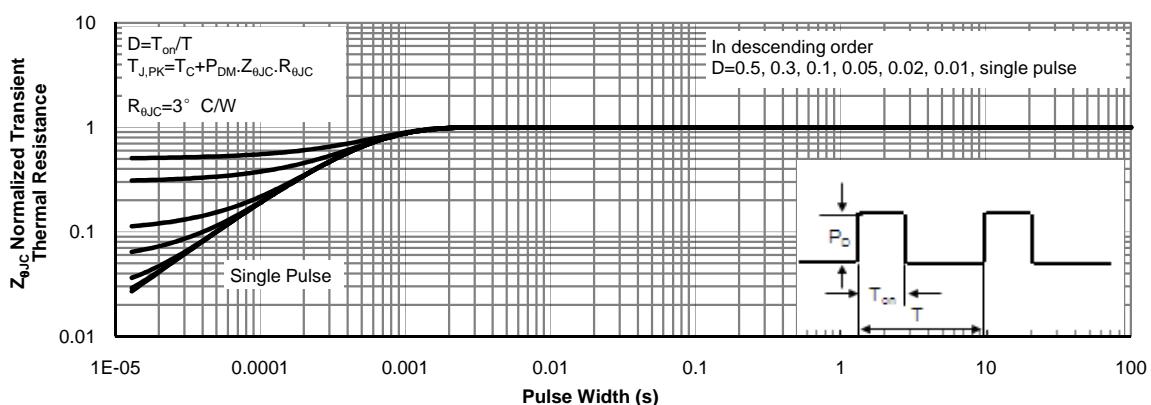


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

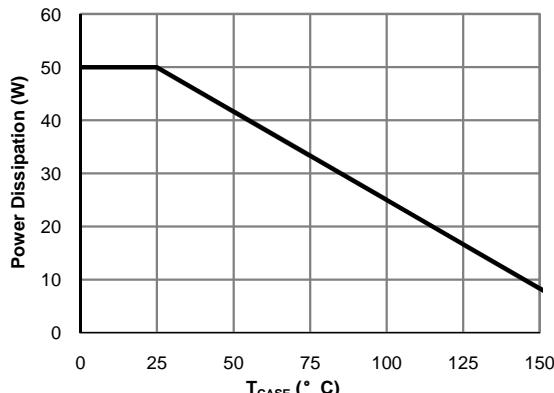


Figure 12: Power De-rating (Note F)

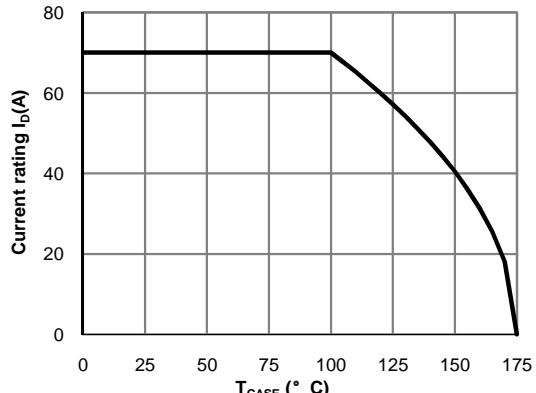


Figure 13: Current De-rating (Note F)

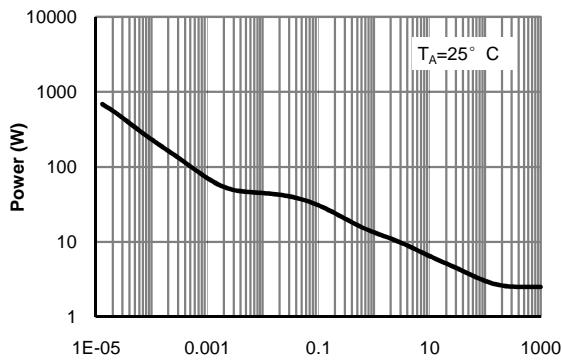


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

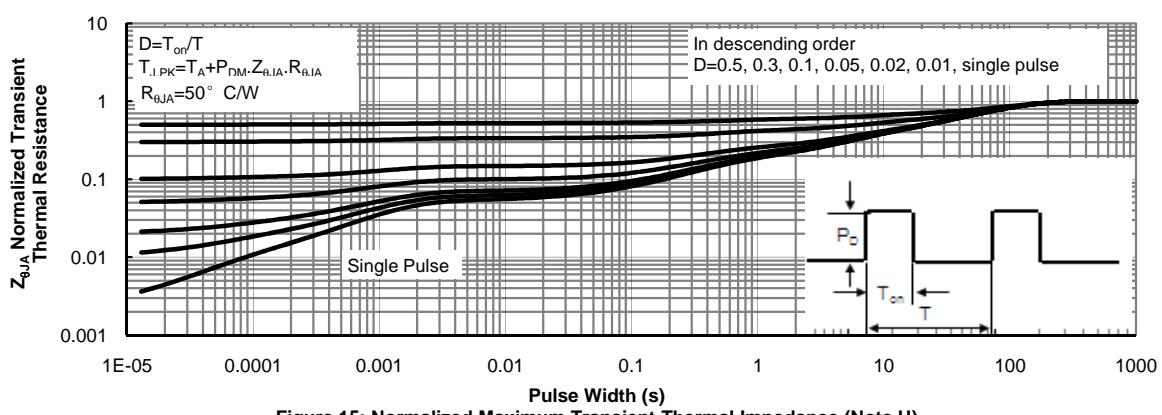
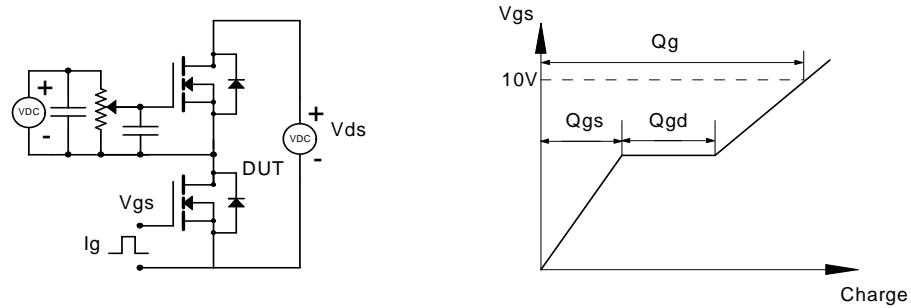
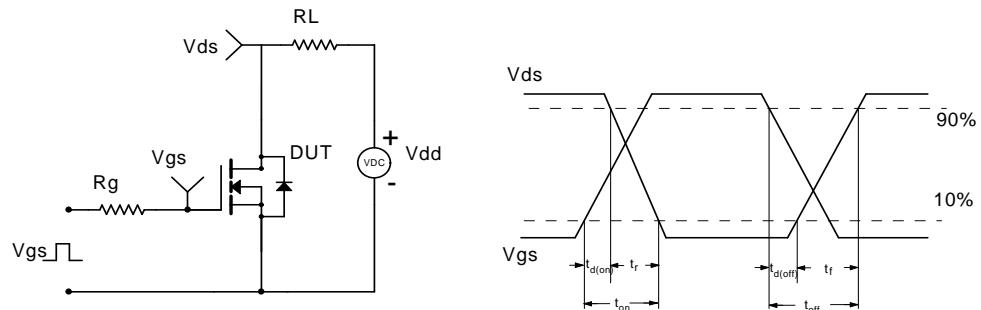


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

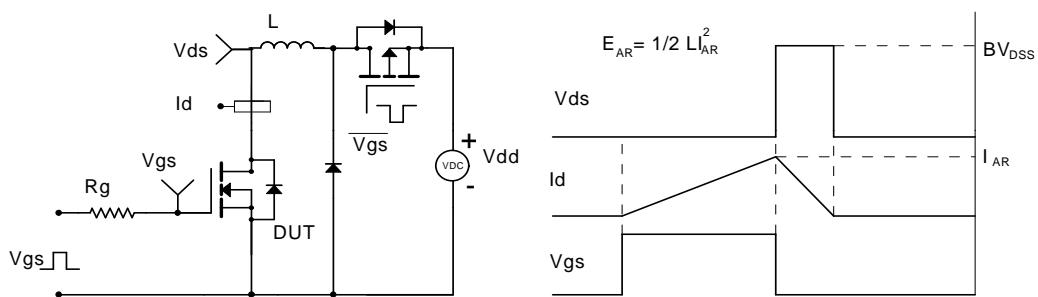
Gate Charge Test Circuit & Waveform



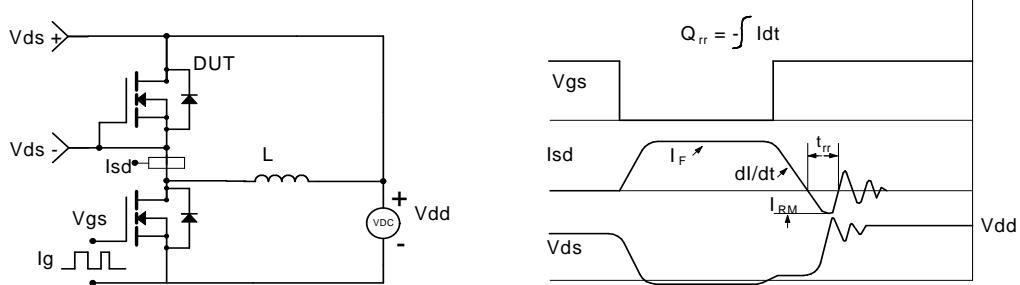
Resistive Switching Test Circuit & Waveforms



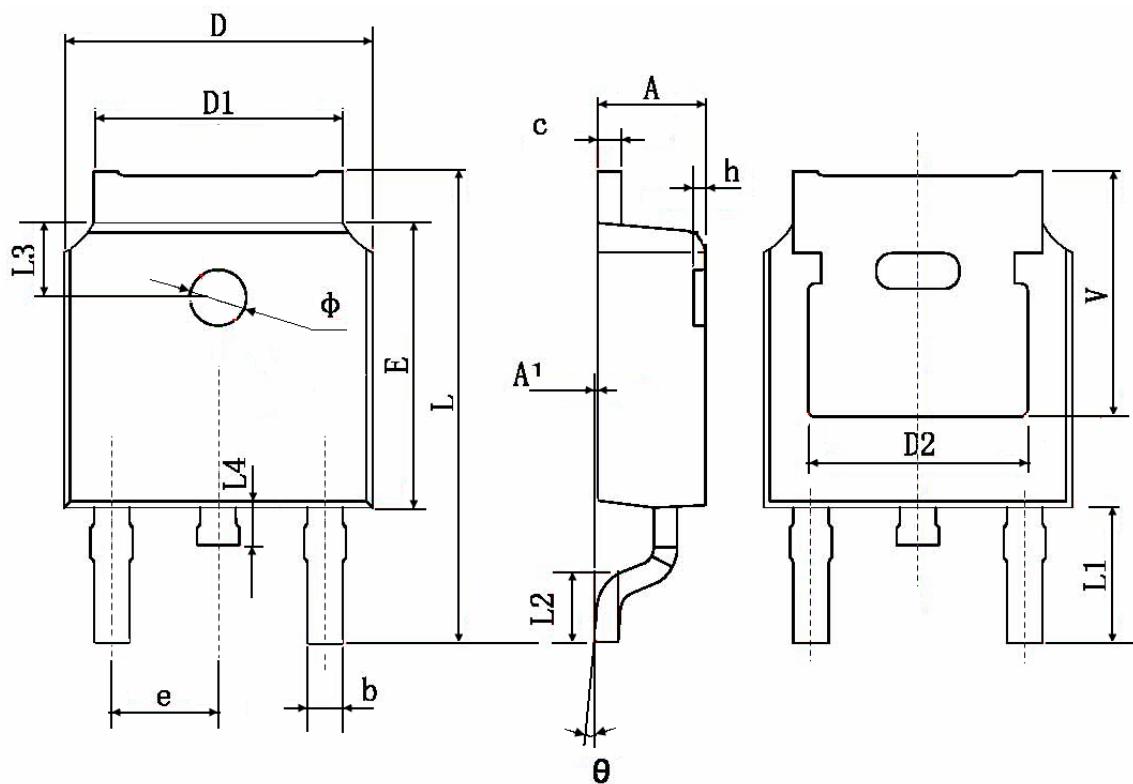
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



TO-252 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	